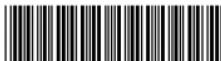


<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10532524	CHEN ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
Emmanuel Bayard	2611	

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
375	316, 340, 341, 324	6/4/2008	EB

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
East	6/4/2008	EB

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
375	316, 340	6/4/2008	EB